

Notice of References Cited	Application/Control No. 10/602,553		Applicant(s)/Patent Under Reexamination MAKOWSKI ET AL.	
	Examiner ISAAC T. TECKLU		Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

RL
3/21/09

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0024211	09-2001	Kudukoli et al.	345/763
*	B	US-2002/0196282	12-2002	Washington et al.	345/763
*	C	US-7,069,517	06-2006	Washington et al.	715/763
*	D	US-2003/0004678	01-2003	Zhang et al.	702/152
*	E	US-7,475,933 7/2008 76 10	11-2006	Washington et al.	715/763
*	F	US-2003/0227483	12-2003	Schultz et al.	345/763
*	G	US-6,690,981	02-2004	Kawachi et al.	700/83
*	H	US-6,102,965	08-2000	Dye et al.	717/109
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	LabVIEW Function and VI Reference Manual", January 1998, pp. 1-609 retrieved from http://www.ni.com/pdf/manuals/321526b.pdf
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.